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Dimensional Optical Metrology and Inspection for Practical Applications VII

**Kevin G. Harding
Song Zhang**
Editors

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Contents

v *Authors*
vii *Conference Committee*

OPTICAL METROLOGY ANALYSIS

- 10667 02 **2D and 3D computational optical imaging using deep convolutional neural networks (DCNNs)** [10667-1]
- 10667 04 **3D shape measurement by thermal fringe projection: optimization of infrared (IR) projection parameters** [10667-3]
- 10667 07 **Motion-induced error compensation for 3D shape measurement with phase shifting technique** [10667-6]

OPTICAL METROLOGY METHODS I

- 10667 09 **Optimal carrier frequency selection for high-speed 3D shape measurement with double-pattern pulse width modulation techniques** [10667-8]
- 10667 0A **High-speed 3D shape measurement by GOBO projection of aperiodic sinusoidal fringes: a performance analysis** [10667-9]

OPTICAL METROLOGY METHODS II

- 10667 0C **Recent research on high-resolution 3D range geometry compression (Invited Paper)** [10667-10]
- 10667 0D **3D shape measurement of glass and transparent plastics with a thermal 3D system in the mid-wave infrared** [10667-11]
- 10667 0E **Improved line of light measurements on shiny and transparent surfaces** [10667-12]
- 10667 0F **Generation and evaluation of hyperspectral 3D surface models based on a structured light system with hyperspectral snapshot mosaic sensors** [10667-13]

OPTICAL METROLOGY APPLICATIONS

- 10667 0G **Superfast high-resolution dynamic 3D strain measurement of robotic flapping wings** [10667-14]
- 10667 0H **Measurement of creep strain in polymers by means of electronic speckle pattern shearing interferometry** [10667-15]

10667 0I **Hand portable 3D mapper applied to pit quantification on aerospace parts** [10667-16]

ADDITIVE METHODS FOR MICRO ELECTRONIC OR FLEXIBLE FEATURES

10667 0K **Error mapping method for multi-axis additive manufacturing system** [10667-17]

10667 0M **Silver nanoparticle electrospray laser deposition for additive manufacturing of microlayers on rigid or flexible substrates** [10667-19]

ADVANCED ADDITIVE MANUFACTURING METHODS

10667 0O **Structured light as an enhancement tool for low contrast features in additive manufacturing** [10667-23]

Authors

Numbers in the index correspond to the last two digits of the seven-digit citation identifier (CID) article numbering system used in Proceedings of SPIE. The first five digits reflect the volume number. Base 36 numbering is employed for the last two digits and indicates the order of articles within the volume. Numbers start with 00, 01, 02, 03, 04, 05, 06, 07, 08, 09, 0A, 0B...0Z, followed by 10-1Z, 20-2Z, etc.

Barragán-Pérez, Omar, 0H
Brahm, Anika, 04, 0D
Bromberg, Vadim, 0K
Castillo, Eduardo A., 0M
Dietrich, Patrick, 0A
Fiorillo, Timothy, 0K
Harding, Kevin, 0E, 0I, 0K, 0O
Heist, Stefan, 04, 0A, 0D, 0F
Kar, Aravinda, 0M
Kühmstedt, Peter, 04, 0A, 0D, 0F
Kumar, Ranganathan, 0M
Landmann, Martin, 04, 0A, 0D
Li, Beiwen, 0G
Liu, Ziping, 07
McDermid, Shawn, 0I
Michtchenko, Alexandre, 0H
Nehmetallah, George, 02
Nguyen, Thanh, 02
Notni, Gunther, 04, 0A, 0D, 0F
Novak, Erik, 0I
Pascual-Francisco, Juan Benito, 0H
Ramamurthy, Rajesh, 0K
Reichwald, Karl, 0F
Schindwolf, Simon, 04, 0D
Susarrey-Huerta, Orlando, 0H
Wang, Yajun, 09
Zhang, Chen, 0F
Zhang, Song, 07, 09, 0C

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- 1 Optical Metrology Analysis
Song Zhang, Purdue University (United States)
- 2 Optical Metrology Methods I
Maik Rosenberger, Technische Universität Ilmenau (Germany)
- 3 Optical Metrology Methods II
Kevin G. Harding, Optical Metrology Solutions (United States)

- 4 Optical Metrology Applications
Song Zhang, Purdue University (United States)
- 5 Additive Methods for Micro Electronic or Flexible Features
Kevin G. Harding, Optical Metrology Solutions (United States)
- 6 Advanced Additive Manufacturing Methods
Kevin G. Harding, Optical Metrology Solutions (United States)